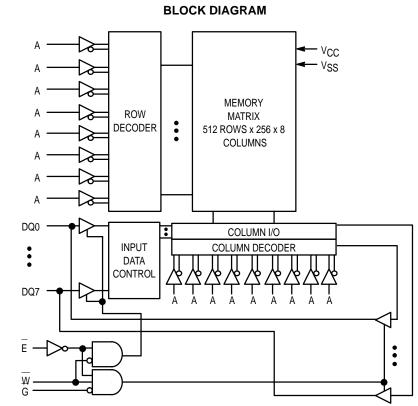
# 128K x 8 Bit Fast Static Random Access Memory

The MCM6726C is a 1,048,576 bit static random access memory organized as 131,072 words of 8 bits. This device is fabricated using high performance silicon–gate BiCMOS technology. Static design eliminates the need for external clocks or timing strobes.

Output enable (G) is a special control feature that provides increased system flexibility and eliminates bus contention problems.

This device meets JEDEC standards for functionality and revolutionary pinout, and is available in a 400 mil plastic small–outline J–leaded package.

- Single 5 V  $\pm$  10% Power Supply
- Fully Static No Clock or Timing Strobes Necessary
- All Inputs and Outputs Are TTL Compatible
- Three State Outputs
- Fast Access Times: 6, 7 ns
- Center Power and I/O Pins for Reduced Noise



# **MCM6726C**



PIN	I ASSIG	NME	ENT
Αd	1	32	D A
АД	2	31	] A
ΑD	3	30	D A
ΑC	4	29	] A
Ē	5	28	] G
	6	27	] DQ7
DQ1 [	7	26	DQ6
Vcc 🛛	8	25	I ∨ <sub>SS</sub>
v <sub>ss</sub> D	9	24	□ v <sub>cc</sub>
DQ2 [	10	23	] DQ5
DQ3 [	11	22	] DQ4
WD	12	21	A
ΑC	13	20	D A
АŪ	14	19	D A
АD	15	18	D A
АЦ	16	17	A
-			

PIN NAMES
A0 - A16 Address Input   E Chip Enable   W Write Enable   G Output Enable   DQ0 - DQ7 Data Input/Output   V <sub>CC</sub> + 5 V Power Supply   V <sub>SS</sub> Ground

IOTOROLA



#### **TRUTH TABLE** (X = Don't Care)

Е	G	w	Mode	V <sub>CC</sub> Current	Output	Cycle
Н	Х	Х	Not Selected	I <sub>SB1</sub> , I <sub>SB2</sub>	High–Z	—
L	Н	Н	Output Disabled	ICCA	High–Z	—
L	L	Н	Read	ICCA	D <sub>out</sub>	Read Cycle
L	Х	L	Write	ICCA	High–Z	Write Cycle

ABSOLUTE MAXIMUM RATINGS (See Note)

Rating	Symbol	Value	Unit
Power Supply Voltage	VCC	– 0.5 to + 7.0	V
Voltage Relative to V <sub>SS</sub> for Any Pin Except V <sub>CC</sub>	V <sub>in</sub> , V <sub>out</sub>	– 0.5 to V <sub>CC</sub> + 0.5	V
Output Current	l <sub>out</sub>	± 30	mA
Power Dissipation	PD	1.5	W
Temperature Under Bias	T <sub>bias</sub>	– 10 to + 85	°C
Operating Temperature	TA	0 to + 70	°C
Storage Temperature — Plastic	T <sub>stg</sub>	– 55 to + 125	°C

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to these high–impedance circuits.

This BiCMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow of at least 500 linear feet per minute is maintained.

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPER-ATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

# DC OPERATING CONDITIONS AND CHARACTERISTICS

(V<sub>CC</sub> = 5.0 V  $\pm$  10%, T<sub>A</sub> = 0 to 70°C, Unless Otherwise Noted)

#### **RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage (Operating Voltage Range)	VCC	4.5	5.0	5.5	V
Input High Voltage	VIH	2.2	_	V <sub>CC</sub> + 0.3**	V
Input Low Voltage	VIL	- 0.5*	_	0.8	V

\* V<sub>IL</sub> (min) = -0.5 V dc; V<sub>IL</sub> (min) = -2.0 V ac (pulse width  $\le 2.0$  ns) for I  $\le 20.0$  mA.

\*\*  $V_{IH}$  (max) =  $V_{CC}$  + 0.3 V dc;  $V_{IH}$  (max) =  $V_{CC}$  + 2 V ac (pulse width  $\leq$  2.0 ns) for I  $\leq$  20.0 mA.

## **DC CHARACTERISTICS**

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, $V_{in} = 0$ to $V_{CC}$ )	l <sub>lkg(l)</sub>		± 1.0	μΑ
Output Leakage Current ( $\overline{E} = V_{IH}$ , $V_{out} = 0$ to $V_{CC}$ )	l <sub>lkg(O)</sub>		± 1.0	μΑ
Output Low Voltage (I <sub>OL</sub> = + 8.0 mA)	VOL	_	0.4	V
Output High Voltage (I <sub>OH</sub> = - 4.0 mA)	VOH	2.4	_	V

## POWER SUPPLY CURRENTS

Parameter	Symbol	MCM6726C-6	MCM6726C-7	Unit	Notes
AC Active Supply Current ( $I_{OUt} = 0$ mA) ( $V_{CC} = max$ , f = f <sub>max</sub> )	ICCA	250	220	mA	1, 2, 3
Active Quiescent Current (E = $V_{IL}$ , $V_{CC}$ = max, f = 0 MHz)	ICC2	100	100	mA	
AC Standby Current (E = $V_{IH}$ , $V_{CC}$ = max, f = f <sub>max</sub> )	I <sub>SB1</sub>	100	100	mA	1, 2, 3
CMOS Standby Current (V <sub>CC</sub> = max, f = 0 MHz, E $\ge$ V <sub>CC</sub> – 0.2 V, V <sub>in</sub> $\le$ V <sub>SS</sub> + 0.2 V, or $\ge$ V <sub>CC</sub> – 0.2 V)	ISB2	60	60	mA	

NOTES:

1. Reference AC Operating Conditions and Characterisitics for input and timing (VIH/VIL, tr/tf, pulse level 0 to 3 V, VIH = 3 V).

2. All addresses transition simultaneously low (LSB) and then high (MSB).

3. Data States are all zero.

#### CAPACITANCE (f = 1.0 MHz, dV = 3.0 V, T<sub>A</sub> = 25°C, Periodically Sampled Rather Than 100% Tested)

Parameter	Symbol	Тур	Max	Unit
Address Input Capacitance	C <sub>in</sub>	_	6	pF
Control Pin Input Capacitance	C <sub>in</sub>	_	6	pF
Input/Output Capacitance	C <sub>I/O</sub>		8	pF

## AC OPERATING CONDITIONS AND CHARACTERISTICS

(V<sub>CC</sub> = 5.0 V  $\pm$ 10%, T<sub>A</sub> = 0 to +70°C, Unless Otherwise Noted)

Input Timing Measurement Reference Level	I.5 V
Input Pulse Levels 0 to 3	3.0 V
Input Rise/Fall Time	2 ns

#### READ CYCLE TIMING (See Notes 1 and 2)

	MCM6726C-6 MCM6726C-7					
Symbol	Min	Max	Min	Max	Unit	Notes
t <sub>AVAV</sub>	6	—	7	—	ns	3
<sup>t</sup> AVQV	—	6	—	7	ns	
<sup>t</sup> ELQV	—	6	—	7	ns	
tGLQV	—	4	—	4	ns	
<sup>t</sup> AXQX	2	—	2	—	ns	
<sup>t</sup> ELQX	3	—	3	—	ns	4,5,6
<sup>t</sup> GLQX	0	—	0	—	ns	4,5,6
<sup>t</sup> EHQZ	—	3	0	3.5	ns	4,5,6
<sup>t</sup> GHQZ	—	3	0	3.5	ns	4,5,6
	tavav tavav tavqv tELQV tGLQV tAXQX tELQX tELQX tELQX tEHQZ	SymbolMintAVAV6tAVQVtELQVtGLQVtAXQX2tELQX3tGLQX0tEHQZ	Symbol   Min   Max     t <sub>AVAV</sub> 6      t <sub>AVQV</sub> 6     t <sub>ELQV</sub> 6     t <sub>ELQV</sub> 6     t <sub>GLQV</sub> 4     t <sub>AXQX</sub> 2      t <sub>ELQX</sub> 3      t <sub>ELQX</sub> 0      t <sub>EHQZ</sub> 3	Symbol   Min   Max   Min     t <sub>AVAV</sub> 6    7     t <sub>AVQV</sub> 6      t <sub>AVQV</sub> 6      t <sub>ELQV</sub> 6      t <sub>ELQV</sub> 4      t <sub>GLQV</sub> 2    2     t <sub>ELQX</sub> 3    3     t <sub>GLQX</sub> 0    0     t <sub>EHQZ</sub> 3   0	Symbol   Min   Max   Min   Max     t <sub>AVAV</sub> 6    7      t <sub>AVQV</sub> 6    7     t <sub>AVQV</sub> 6    7     t <sub>ELQV</sub> 6    7     t <sub>GLQV</sub> 4    4     t <sub>AXQX</sub> 2    2      t <sub>ELQX</sub> 3    3      t <sub>GLQX</sub> 0    0      t <sub>EHQZ</sub> 3   0   3.5	Symbol   Min   Max   Min   Max   Unit     t <sub>AVAV</sub> 6    7    ns     t <sub>AVAV</sub> 6    7    ns     t <sub>AVQV</sub> 6    7   ns     t <sub>AVQV</sub> 6    7   ns     t <sub>ELQV</sub> 6    7   ns     t <sub>GLQV</sub> 4    4   ns     t <sub>AXQX</sub> 2    2    ns     t <sub>AXQX</sub> 2    3    ns     t <sub>ELQX</sub> 3    3    ns     t <sub>GLQX</sub> 0    0    ns     t <sub>EHQZ</sub> 3   0   3.5   ns

NOTES:

1. W is high for read cycle.

2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.

3. All read cycle timings are referenced from the last valid address to the first transitioning address.

4. At any given voltage and temperature, t<sub>EHQZ</sub> max < t<sub>ELQX</sub> min, and t<sub>GHQZ</sub> max < t<sub>GLQX</sub> min, both for a given device and from device to device.

5. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.

6. This parameter is sampled and not 100% tested.

Figure 1A

7. Device is continuously selected (E =  $V_{IL}$ , <u>G</u> =  $V_{IL}$ ).

8. Addresses valid prior to or coincident with E going low.

## AC TEST LOADS

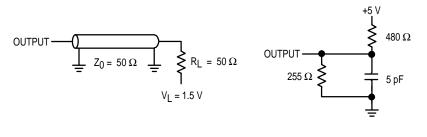
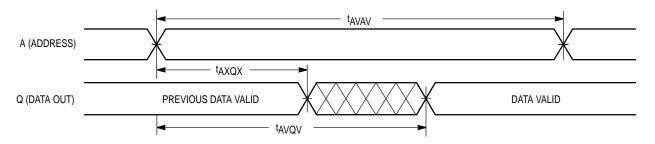


Figure 1B

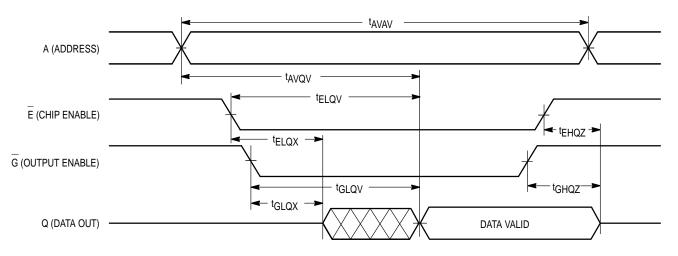
#### TIMING LIMITS

The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the device never provides data later than that time.

# READ CYCLE 1 (See Note 7)







# WRITE CYCLE 1 ( $\overline{W}$ Controlled, See Notes 1 and 2)

		MCM67	MCM6726C–6 MCM6726C–7				
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t <sub>AVAV</sub>	6	—	7	—	ns	3
Address Setup Time	tAVWL	0	—	0	—	ns	
Address Valid to End of Write	<sup>t</sup> AVWH	6	—	7	—	ns	
Address Valid to End of Write, G High	<sup>t</sup> AVWH	6	—	7	—	ns	
Write Pulse Width	<sup>t</sup> WLWH <sup>t</sup> WLEH	6	—	7	—	ns	
Write Pulse Width, G High	<sup>t</sup> WLWH <sup>t</sup> WLEH	6	_	7	_	ns	
Data Valid to End of Write	<sup>t</sup> DVWH	3	—	3.5	—	ns	
Data Hold Time	tWHDX	0	—	0	—	ns	
Write Low to Data High–Z	tWLQZ	0	3.5	0	3.5	ns	4,5,6
Write High to Output Active	tWHQX	3	—	3	—	ns	4,5,6
Write Recovery Time	tWHAX	1	—	1	—	ns	

NOTES:

1. A write occurs during the overlap of  $\overline{E}$  low and  $\overline{W}$  low.

2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.

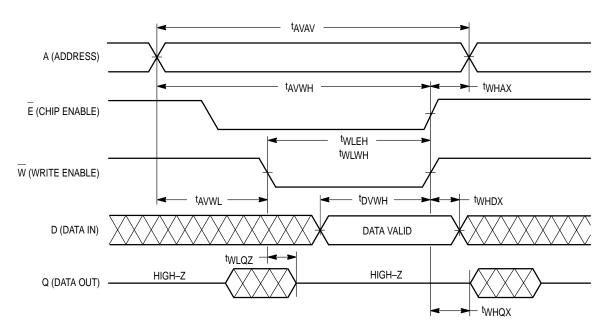
3. All write cycle timings are referenced from the last valid address to the first transitioning address.

4. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.

5. This parameter is sampled and not 100% tested.

6. At any given voltage and temperature, tWLQZ max < tWHQX min both for a given device and from device to device.

## WRITE CYCLE 1



# WRITE CYCLE 2 (E Controlled, See Notes 1 and 2)

		MCM6726C-6		MCM6726C-7			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t <sub>AVAV</sub>	6		7		ns	3
Address Setup Time	<sup>t</sup> AVEL	0	_	0	_	ns	
Address Valid to End of Write	<sup>t</sup> AVEH	6	—	7	_	ns	
Enable to End of Write	<sup>t</sup> ELEH <sup>t</sup> ELWH	5	_	6	_	ns	4,5
Data Valid to End of Write	<sup>t</sup> DVEH	3		3.5		ns	
Data Hold Time	<sup>t</sup> EHDX	0		0		ns	
Write Recovery Time	<sup>t</sup> EHAX	0		0		ns	

NOTES:

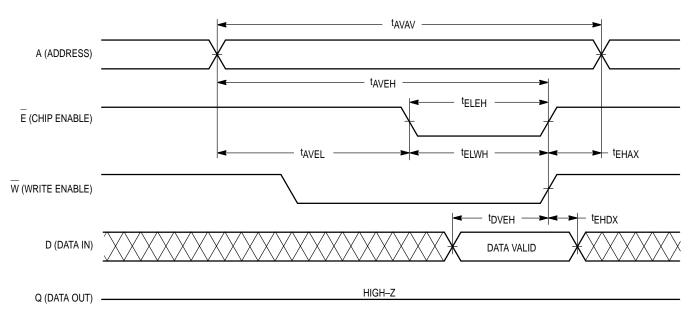
1. A write occurs during the overlap of  $\overline{E}$  low and  $\overline{W}$  low.

2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.

3. All\_write cycle timings are referenced from the last valid address to the first transitioning address.

4. If <u>E</u> goes low coincident with or after W goes low, the output will remain in a high impedance condition.

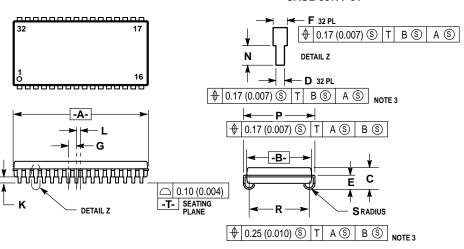
5. If E goes high coincident with or before W goes high, the output will remain in a high impedance condition.



## WRITE CYCLE 2

### PACKAGE DIMENSIONS

#### 32-LEAD 400 MIL SOJ CASE 857A-01

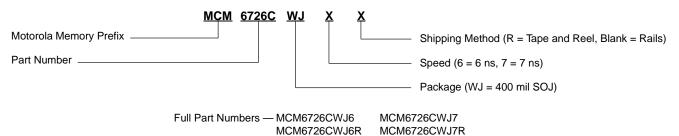


- NOTES
  - DIMENSIONING AND TOLERANCING PER ANSI 1. Y14.5M, 1982. CONTROLLING DIMENSION: INCH

  - TO BE DETERMINED AT PLANE -T-. DIMENSION A & B DO NOT INCLUDE MOLD 3 4.
  - PROTRUSION. MOLD PROTRUSION SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
  - DIMENSION A & B INCLUDE MOLD MISMATCH AND ARE DETERMINED AT THE PARTING LINE.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	20.83	21.08	0.820	0.830
В	10.03	10.29	0.395	0.405
С	3.26	3.75	0.128	0.148
D	0.41	0.50	0.016	0.020
E	2.24	2.48	0.088	0.098
F	0.67	0.81	0.026	0.032
G	1.27 BSC		0.050 BSC	
K	0.89	1.14	0.035	0.045
L	0.64 BSC		0.025 BSC	
N	0.89	1.14	0.035	0.045
Р	11.05	11.30	0.435	0.445
R	9.27	9.52	0.365	0.375
S	0.77	1.01	0.030	0.040

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HONG KONG: Motorola Semiconductors H.K. Ltd.; 8B Tai Ping Industrial Park, 51 Ting Kok Road, Tai Po, N.T., Hong Kong. 852–26629298

